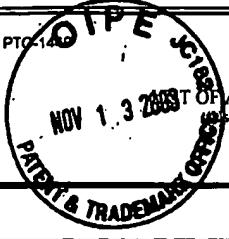


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| Form PTO-1449 | | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. MI22-2356 | | priority SERIAL NO. 10/364,054 | |
|---|----|------------------|---|-------------------|-------------------------------|----------|-----------------------------------|----|
| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | APPLICANT Luan C. Tran | | | | | |
| | | | priority FILING DATE February 10, 2003 | | priority GROUP 2812 | | | |
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| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| GU | AA | 6,458,666 B2 | 10-2002 | Wasshuber | | | | |
| GU | AB | 6,444,548 B2 | 09-2002 | Divakaruni et al. | | | | |
| GU | AC | 3,886,003 | 05-1975 | Takagi et al. | | | | |
| GU | AD | 4,366,338 | 12-1982 | Turner et al. | | | | |
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| GU | AG | US2001/0036713A1 | 11-01-2001 | Rodder et al. | | | July 5, 2001 | |
| GU | AH | US2002/0034865A1 | 03-21-2002 | Umimoto et al. | | | Nov. 30, 2001 | |
| GU | AI | 09/876,722 | | Scott | | | June 6, 2001 | |
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| | AK | | | | | | | |
| | AL | | | | | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | | |
| | | Document Number | Date | Country | Class | Subclass | Translation | |
| | | | | | | | Yes | No |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | | |
| GU | AQ | | Young et al., "A 0.13 μm CMOS Technology with 193 nm Lithography and Cu/Low-k for High Performance Applications", IEDM, pgs. 563-566, April 2000. | | | | | |
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| EXAMINER <i>Jennifer M. Kennedy</i> | | | DATE CONSIDERED <i>Feb. 15, 2005</i> | | | | | |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | | |

1/3 IDS 11/13/03

| Form PTO-144  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | | | ATTY. DOCKET NO. MI22-2356 | SERIAL NO. 10/624,628 | | |
|--|----|-----------------|---------|--|--------------------------|----------|----------------------------|
| | | | | APPLICANT Luan C. Tran | | | |
| | | | | FILING DATE July 21, 2003 | GROUP 2812 | | |
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| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
| QH | AA | 6,144,079 A | 11-2000 | Shirahata et al. | | | |
| QH | AB | 6,033,952 | 03-2000 | Yasumura, et al. | | | |
| QH | AC | 6,124,168 | 09-2000 | Ong | | | |
| QH | AD | 5,688,705 | 11-1997 | Bergemont | | | |
| QH | AE | 5,866,448 | 02-1999 | Pradeep et al. | | | |
| QH | AF | 5,858,847 | 01-1999 | Zhou et al. | | | |
| QH | AG | 6,380,598 | 04-2002 | Chan | | | |
| QH | AH | 6,060,364 | 05-2000 | Maszara et al. | | | |
| QH | AI | 6,194,276 B1 | 02-2001 | Chan et al. | | | |
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| QH | AK | 5,164,806 | 11-1992 | Nagatomo et al. | | | |
| QH | AL | 4,937,756 | 06-1990 | Hsu et al. | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | | Document Number | Date | Country | Class | Subclass | Translation |
| QH | AM | EP 0718881 | 06/96 | EPO, Chan | | | Yes No |
| | AN | | | | | | |
| | AO | | | | | | |
| | AP | | | | | | |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
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| EXAMINER <i>Jennifer M. Kennedy</i> | | | | DATE CONSIDERED <i>Feb 15, 2005</i> | | | |
| <small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small> | | | | | | | |

2/3 IDS 11/13/03

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|--|----|-----------------|--|-------------------------------|--------------------------|----------|----------------------------|
| | | | | APPLICANT Luan C. Tran | | | |
| | | | | FILING DATE July 21, 2003 | GROUP 2812 | | |
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| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
| QH | AA | 5,930,614 | 07-1999 | Eimori et al. | | | |
| QH | AB | 5,635,744 | 06-1997 | Hidaka et al. | | | |
| QH | AC | 6,204,536 | 03-2001 | Maeda et al. | | | |
| QH | AD | 6,515,899 B1 | 02-2003 | Tu et al. | | | |
| QH | AE | 4,570,331 | 02-1986 | Eaton, Jr. et al. | | | |
| QH | AF | 6,429,079 B1 | 08-2002 | Maeda et al. | | | |
| QH | AG | 6,607,979 B1 | 08-2003 | Kamiyama | | | |
| QH | AH | 4,686,000 | 08-1987 | Heath | | | |
| QH | AI | 5,814,875 | 09-1998 | Kumazaki | | | |
| QH | AJ | 5,654,573 | 08-1997 | Oashi et al. | | | |
| QH | AK | 6,479,330 B2 | 11-2002 | Iwamatsu et al. | | | |
| QH | AL | 6,586,803 | 07-2003 | Hidaka et al. | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | | Document Number | Date | Country | Class | Subclass | Translation |
| | AM | | | | | | Yes |
| | AN | | | | | | No |
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| | AP | | | | | | |
| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
| QH | AR | | CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/Issues/1999/sep99/docs/feature1.asp on 3/29/2001: "Resists Join the Sub-_A Revolution", 9 pgs. | | | | |
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| EXAMINER <i>George M. Kennedy</i> DATE CONSIDERED <i>Feb 15, 2005</i> <i>Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</i> | | | | | | | |

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Sheet 3 of 3

| Form PTO-1449  LIST OF ART CITED BY APPLICANT <small>(use several sheets if necessary)</small> | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. MI22-2356 | SERIAL NO. 10/624,628 | | |
|---|--------------------------|--|--|-------------------------------|--------------------------|----------------------|----------------------------|
| | | APPLICANT Luan C. Tran | | | | | |
| | | FILING DATE July 21, 2003 | | GROUP 2812 | | | |
| | | U.S. PATENT DOCUMENTS | | | | | |
| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
| QH | AA | 6,552,401 B1 | 04-2003 | Dennison | | | |
| QH | AB | 6,627,524 B2 | 09-2003 | Scott | | | |
| QH | AC | US2002/0182829A1 | 12-2002 | Chen | | | |
| QH | AD | US2002/0164846A1 | 11-2002 | Lin et al. | | | Apr. 19, 2002 |
| QH | AE | US2003/0071310A1 | 04-2003 | Salling et al. | | | Oct. 11, 2001 |
| | AF | | | | | | |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
| QH | AR | | <i>"Session 18: Integrated Circuits and Manufacturing - DRAM and Embedded DRAM Technology," 2001 IEDM Technical Program, 2001 IEEE International Electron Devices Meeting, Dec. 4, 2001, reprinted 11/15/01 from http://www.his.com/~iedm/techprogram/sessions/s18.html, pp. 1-2.</i> | | | | |
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| EXAMINER | <i>George M. Kennedy</i> | | | DATE CONSIDERED | | <i>Feb. 15, 2005</i> | |
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| Form PTO-1449 | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. M122-2356 | SERIAL NO. 10/024623 | | | |
|---|----------|--|--------------|-------------------------------|-------------------------|-------------|----------------------------|----|
| LIST OF ART CITED BY APPLICANT (List several lines if necessary) | | APPLICANT Lynn C. Trnn | | | | | | |
| | | FILING DATE July 21, 2003 | | GROUP 2011 | | | | |
| U.S. PATENT DOCUMENTS | | | | | | | | |
| Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate | |
| GU | AA | 6,521,487 B1 | 02-2003 | Chen et al. | | | | |
| GU | AB | 6,492,444 B2 | 12-2002 | Nobbe et al. | | | | |
| GU | AC | 6,468,865 B1 | 10-2002 | Yang et al. | | | | |
| Opt | AD | 6,451,704 B1 | 09-2002 | Pradeep et al. | | | | |
| GU | AE | 6,436,747 B1 | 08-2002 | Segawa et al. | | | | |
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| GU | AH | 5,973,473 | 07-1999 | Roland | | | | |
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| GR | AJ | 6,162,405 H1 | 01-2001 | Yu et al. | | | | |
| GU | AK | 6,209,510 B1 | 03-2001 | Ahmed et al. | | | | |
| GU | AL | US2003/0030112A1 | 02-2003 | Wada et al. | | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | Translation | | |
| | | Document Number | Date | Country | Class | Subclass | Yes | No |
| AM | | | | | | | | |
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| <i>Junif M. Kennedy</i> | | | Feb 15, 2005 | | | | | |
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Form PTO-1449

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
N122-2336SERIAL NO.
10524,628LIST OF ART CITED BY APPLICANT
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U.S. PATENT DOCUMENTS

| *Examiner Initials | | Document Number | Date | Name | Class | Section | Filing Date If Appropriate |
|--------------------|----|-----------------|---------|---------------|-------|---------|----------------------------|
| OM | AM | 5,841,185 | 11-1998 | Ishikawa | | | |
| OM | AD | 6,331,458 B1 | 12-2001 | Aojima et al. | | | |
| OM | AC | 6,251,744 B1 | 06-2001 | Suzuki et al. | | | |
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FOREIGN PATENT DOCUMENTS

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George M. Kennedy Feb. 15, 2005

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5098383424 P.03/03

| Form PTO-1449 | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. M022-2156 | SERIAL NO. 10624,629 | | |
|--|----|--|---------|-------------------------------|-------------------------|----------|---------------------------|
| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT Lien C. Tran | | | |
| | | | | PILING DATE July 21, 2003 | GROUP 2811 | | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Piling Date If Applicable |
| CH | AA | 5,767,537 | 06-1998 | Kizilyalli | | | |
| CH | AB | 5,369,215 | 11-1994 | Vusal | | | |
| CH | AC | 5,397,840 | 03-1995 | Murichi | | | |
| CH | AD | 5,493,728 | 04-1997 | Hidaka | | | |
| CH | AE | 5,672,526 | 09-1997 | Kawamura | | | |
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| CH | AI | 5,830,226 | 01-1999 | Wu | | | |
| CH | AJ | 5,877,056 | 03-1999 | Wu | | | |
| CH | AK | 6,516,113 B1 | 02-2003 | Beyoochi | | | |
| CH | AL | 6,642,361 B2 | 11-2003 | Matsuda et al. | | | |
| CH | AM | 6,297,082 D1 | 10-2001 | Lin et al. | | | |
| CH | AN | US2002/004392A1 | 04-2002 | Maeda et al. | | | |
| CH | AO | US2002/0169231 | 10-2003 | Clevenger et al. | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | | Document Number | Date | Country | Class | Subclass | Translation |
| | AP | | | | | | Yes |
| | AQ | | | | | | No |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Page, Etc.) | | | | | | | |
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